HIGH PRECISION ELECTRIC GATE FOR TIME-OF-FLIGHT ION MASS SPECTROMETERS

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ABSTRACT
A time-of-flight mass spectrometer having a chamber with electrodes to generate an electric field in the chamber and electric gating for allowing ions with a predetermined mass and velocity into the electric field. The design uses a row of very thin parallel aligned wires that are pulsed in sequence so the ion can pass through the gap of two parallel plates, which are biased to prevent passage of the ion. This design by itself can provide a high mass resolution capability and a very precise start pulse for an ion mass spectrometer. Furthermore, the ion will only pass through the chamber if it is within a wire diameter of the first wire when it is pulsed and has the right speed so it is near all other wires when they are pulsed.

20 Claims, 4 Drawing Sheets
FIG. 4

1. START

2. CREATE POTENTIAL

3. ENABLE ELECTRIC GATE

4. RECEIVE START PULSE

5. ENERGIZE ELECTRODES SEQUENTIALLY

6. TOF ANALYSIS

7. ION MASS SPECTRUM ANALYSIS
The present invention relates to a mass spectrometer in general and in particular to a high precision electric gate for a time-of-flight (TOF) ion mass spectrometer (IMS).

FIELD OF THE INVENTION

The present invention relates to a mass spectrometer in general and in particular to a high precision electric gate for a time-of-flight (TOF) ion mass spectrometer (IMS).

BACKGROUND OF THE INVENTION

Mass spectrometers are used extensively in the scientific community to measure and analyze the chemical compositions of substances. In general, a mass spectrometer is made up of a source of ions that are used to ionize neutral atoms or molecules from a solid, liquid, or gaseous substance, a mass analyzer that separates the ions in space or time according to their mass or their mass-per-charge ratio, and a detector. Several variations of mass spectrometers are available, such as magnetic sector mass spectrometers, quadrupole mass spectrometers, and time-of-flight ion mass spectrometers.

Time-of-flight ion mass spectrometers (TOF-IMS) can detect ions over a wide mass range simultaneously. Mass spectra are derived by measuring the times for individual ions to traverse a known distance through an electrostatic field free region. In general, the mass of an ion is derived in TOF-IMS by measurement or knowledge of the energy, E, of an ion, measurement of the time, t1, that an ion passes a fixed point in space, P1, and measurement of the later time, t2, that the ion passes a second point, P2, in space located at a predetermined distance, d, from P1. Using an ion beam of known energy-per-charge E/q, the time-of-flight (t$_{TOF}$) of the ion is t$_{TOF}$=d/E, and by the ion speed. In a gated TOF-IMS uncertainty in t$_{TOF}$ may result, for example, from ambiguity in the exact time that an ion entered the spectrometer.

One method of attempting overcome this limitation in TOF-IMS utilizes a thin foil located at the entrance to spectrometer. The thin foil method works best with ions having sufficient energy to traverse the foil. Secondary electrons generated by the interaction of the ion with the foil are detected and provide an indication of when the ion entered the spectrometer. However, the foil method is not without its own limitations. These limitations include the requirement that the incident ion have sufficient energy to transit the foil, the energy degradation of the sample ion due to interaction with the foil, and the angular scattering of the sample ion due also to its interaction with the foil.

For the reasons stated above, and for other reasons stated below which will become apparent to those skilled in the art upon reading and understanding the present specification, there is a need in the art for resolving when the time that at least one ion entered the spectrometer without substantially reducing the energy of the at least one ion.

BRIEF DESCRIPTION OF THE INVENTION

The above-mentioned shortcomings, disadvantages and problems are addressed herein, which will be understood by reading and studying the following specification.
The main challenge for size reduction is the process-teture, wind estimate and spacecraft potential estimate. Once
be used to make miniature mass spectrometers of high capa-
the sample of material. The ionizing source 150 can also be a
to an embodiment. The TOF-IMS
trometer (TOF-IMS)
ng hardware, miniature pulse generator, and miniature HV 
sourced to the TOF section. The use of the energy
analyzer removes the uncertainty in the ion mass since atmo-
t 295 to 305pheric winds, thermal width of ion distribution function and
spheric winds, thermal width of ion distribution function and
The disclosed embodiments include a time-of-flight mass
able to make miniature mass spectrometers of high capa-
for short term usage (getter pumps can be baked out for
The electric gating can be used for all ion and neutral mass

trometer having a chamber with electrodes to generate an
electric field in the chamber and electric gating for allowing
microchannel plate detector or a fast secondary emission

tation for all ion and neutral mass
multiplier (SEM) where first converter plate (dynode) is flat.
The electrical signal from the detector is recorded by means of

torneter

time-of-flight ion mass spectrometer (TOF-IMS) in accor-
dance to an embodiment. The TOF-IMS 100 comprises an electric
gate 110, a time-of-flight mass analyzer 120, a detection
circuitry 140, and an ionizing source 150 at the entrance opening to the electric gate and a signal output 160 at the
detection circuitry.

The ionizing source 150 can be any radiation source, such as
a laser radiation source, an electron beam, an ion source, a
fast (energetic) atom source, or an ion source generated by a
natural source or by the interaction of materials that causes
ions to be generated or emitted. Similarly, the ions to be
analyzed can also be generated by impinging an ion beam on the
sample of material. The ionizing source 150 can also be a
plasmatron, i.e., a plasma discharge ion source which can, for
example, use radio-frequency to induce ionization and for-
A voltage (VP) is applied across the opposite plates along
A voltage (VP) is applied across the opposite plates along

FIG. 2 is an illustration of the electric gate 110 for a
time-of-flight ion mass spectrometer (TOF-IMS) in accor-
dance to an embodiment. The electric gate comprises oppos-
te plates 210 & 220, a plurality of wires 240 aligned a
common axis, a field programmable array 280, a voltage
source (VP), and switching circuitry 285 for sequentially
energizing the plurality of electrodes. The electric gate can be
encased in chamber with an entrance opening and an exit
opening. The electric gate includes at least two parallel plates separated by gap 250. One of the opposite plates includes
a plurality or series of electrodes/wires 240 that can range from
1 to 30 microns in diameter. The wires are aligned along an
axis (Y-axis shown) direction and spaced a predetermined
distance apart 256 microns apart in a second axis (X-axis
shown). The gap between the opposite plates is about 75
microns. The number of wires and diameter of the wires is
based on the desired precision. The opposite plates are biased
so ions cannot pass through, deflected up towards wires,
unless when they pass each wire they are pushed away from the
top plate, if the wire is pulsed at just the right time. The
precision is given by the wire diameter over ion speed and the
precision of each pulse (260,265) which is around 0.2 ns
(nanoseconds). Then as the ion passes each wire they are
pushed away, if the wire is pulsed as they pass each wire, and
the ions have right time of entry and right speed they pass
through the gate. With 1 mil (25.4 micron) wires the spect-
rometer 100 has a mass resolution capability of
M/dM>1000. A 12-15 micron wire the spectrometer 100 has a
mass resolution capability of M/dM>10000.

A voltage (VP) is applied across the opposite plates along a
third axis (Z-axis) such that heavier ions 290 will require a
higher voltage. The voltage (VP) is such that an ion moving in the direction of the second axis (X-axis) cannot successfully pass through the gap between the plates because the ion would be deflected downward (Z direction). The voltage source (VP) creates an electric potential across the opposite plates to deflect ions away from the entrance opening. The wires 240 are pulsed in sequence just when the ion passes each wire and pushes ion away from top plate 220. Without the series of pulses the ion cannot pass through the gate. The wires can be referred to as push electrodes and the applied voltage 260 (VT). The VP and VT voltages will be proportional to the ion mass (M). Furthermore, the ion 290 will only pass through the gate if is within a wire diameter of the first wire when it is pulsed and has the right speed so it is near all the other wires when they are pulsed. The time (dt) between pulses 265 is set by the distance between wires 245 (dw) and the ion speed (v). The pulse generator or FPGA 280 needs to be able to provide fast pulses with widths varying between 1 ns and 100 ns and be able to space pulse from a 1 ns to 100 ns. The max number of pulses per event is 20 wires. Since the initial ion speed determines whether the ion will be at the required wire when it is being energized the gate acts as a velocity filter. The ion can be pre-accelerate the ions by VPA=0.5*MV^2 and using the mass to charge ratio one can produce a miniature mass spectrometer. A field programmable array (FPGA) 280 can cause control voltages VP and VT, the width and amplitude of the pulse 260, and the time between each pulse 265 at a particular pulse frequency. The FPGA can activate switch 270 to cause voltage VP to be applied across the opposite plates. An external controller 299 can also be used to activate switch 270, activate FPGA 280, and can be used to program the properties of the series of pulses so to select an ion having a desired mass (m) and a desired velocity (v).

Various techniques are described for high resolution time measurement using a programmable controller, such as an FPGA. The timing may be triggered by any event, depending on the applications of use. However, once triggering has occurred, a start pulse begins propagating through the FPGA. Ordinarily, propagation would be along columns of the array of circuit elements in the FPGA. Yet some of the present techniques stagger pulse propagation across different columns of the FPGA, to maximize the amount of time delay that may be achieved while minimizing the overall array size (and thus minimizing the environmental imprint) of the FPGA. The FPGA design has the capability of using a single start pulse to trigger timing measurement and multiple stop pulses to allow the time difference to be determined between many different events, without resetting timing operation. In this way the FPGA can be used as a timer to determine an elapsed time of at least one ion at a predetermined location after the exit opening just from the start pulse minus the stop pulse \((t_{stop}-t_{start})\). The FPGA takes snapshots of its entire staggered delay line propagation each clock cycle and from this edge transitions are determined and timing between start and stop pulses are determined. By using a technique that may be used on small array sized FPGAs operating at relatively fast clock rates, high resolution time measurements between start and stop event can be performed in the nanosecond and sub-nanosecond range. For example, systems may be designed for TOF applications that require accuracies of 0.5 ns or better (from delay lines between 10 and 20 ns total) with adjustability up to at least 100 ns, for peak measurement rates of 100,000 events/second and higher.

FIG. 3 illustrates an example FPGA 280 that may be configured to perform gating, generation of the series of pulses, or perform time-of-flight analysis. The FPGA 280 includes a plurality of identical unit circuits (limited number is shown for brevity) that operate as configurable logic blocks 302 (CLBs) as also shown. The FPGA 280 may be programmed using known techniques and to form functional circuit elements as discussed below. In general, each unit circuit comprises a CLB 302, and each CLB 302 which is constructed of two segments. Each unit circuit receives a clock signal 302, in this case a 1-100 MHz clock signal and uses that clock signal to drive data storage in its segments, each comprising a flip flop-based shift register or slice. Segment 315 includes slices S0, S1. The FPGA 280 is configured for input signals 305 entering the bottom of the FPGA 2280 to propagate along vertical columns of the FPGA. The CLB 302 receives an input signal for the respective row either from a preceding CLB or direct column entry like from external controller 299. The CLB 302 propagates that signal via a known delay through segments to the next circuit unit (not shown), in the column. The output 310 from segment 316 is coupled to a specific one of the plurality of wires 240 in plate 220. Each column will have a propagation time depending in part on the number of rows in the FPGA so as to be able to apply the pulse to the dedicated wire on plate 220. For small enough FPGAs, that column propagation time may be only the order of nanoseconds, for example, approximately 6 ns. However, while short propagation times are desirable for high resolution timing circuits, a signal in each column would traverse an entire column of the FPGA 280 and thus escape without detection before a single clock cycle has passed, depending on the speed of the FPGA clock. Delays could be introduced to cause the pulse to appear at the desired interval in the gating process.

FIG. 4 is flowchart of method 400 for gating an ion mass spectrometer in accordance to an embodiment. Method 400 begins with a call to start the process at action 405. In action 410, a potential is created across opposite plates 210 and 220. As noted with reference to FIG. 2, the potential is voltage VP. In action 415, the electric gate is enabled by the injection of the start pulse from FPGA 280. This electrical signal causes an opening event to occur allowing at least one ion to enter the chamber through the entrance opening. However, only ions within one wire diameter (12.5 microns) 295 from the first wire will be able to enter the chamber and possible make it to the exit opening of the chamber. In action 420, the start pulse is readily available from the FPGA timing sequence as note in FIG. 3. In action 425, the electrodes or wires are sequentially pulsed by the FPGA. The electrodes are thus individually energized and ions that are too slow are stopped because they do not reach the pulsed wire in time for the opening event. In the case of ions that are fast enough to reach the wire slightly before the wire is pulse receive a push that is proportional to \(V_{P}=0.5*MV^2\). In action 430 a time-of-flight analysis is performed by using the start pulse (FPGA) and the stop pulse (FPGA) or detection from a device upstream from the electronic gate 110. In action 435, a ion mass spectrum analysis can be performed from the capture timing data and the detection of the at least one ion at a suitable detector.

Embodiments as disclosed herein may also include computer-readable media for carrying or having computer-executable instructions or data structures stored thereon for operating such devices as controllers 299, sensors, and electromechanical devices. Such computer-readable media can be any available media that can be accessed by a general purpose or special purpose computer. By way of example, and not limitation, such computer-readable media can comprise RAM, ROM, EEPROM, CD-ROM or other optical disk stor-
an electric field pushes the at least one ion away from the plate having the plurality of electrodes.

4. The method of claim 3, wherein the temporal pulse width is between 1 ns to 100 ns.

5. The gating apparatus of claim 4, wherein the electric gate is a field programmable gate array.

6. The gating apparatus of claim 5, wherein the electrical signal pushes the at least one ion away from the plate having the plurality of electrodes.

7. The gating apparatus of claim 5, wherein a start time for time-of-flight analyses is the pulse applied to the electrode closest to the entrance opening of the chamber.

8. A method for gating an ion mass spectrometer comprising:

9. The method of claim 8, wherein the electrical signal is a plurality of pulses with temporal pulse width and the plurality of pulses are applied at a pulse frequency.

10. The method of claim 9, wherein the pulse frequency is a function of the position of the plurality of electrodes and ion velocity.

11. The method of claim 10, wherein the temporal pulse width is between 1 ns to 100 ns and the pulse frequency is between 2 ns to 100 ns.

12. The method of claim 11, wherein the electric signal is applied by a field programmable gate array.

13. The method of claim 12, wherein the electrical signal pushes the at least one ion away from the plate having the plurality of electrodes.

14. The method of claim 13, wherein a start time for time-of-flight analyses is the pulse applied to the electrode closest to the entrance opening of the chamber.

15. A time-of-flight ion mass spectrometer comprising:

16. The time-of-flight ion mass spectrometer of claim 15, wherein the field programmable array generates a plurality of pulses with temporal pulse width and the plurality of pulses are applied at a pulse frequency.

17. The time-of-flight ion mass spectrometer of claim 16, wherein the pulse frequency is a function of the position of the plurality of electrodes and ion velocity.

18. The time-of-flight ion mass spectrometer of claim 16, wherein the temporal pulse width is between 1 ns to 100 ns and the pulse frequency is between 2 ns to 100 ns.

19. The time-of-flight ion mass spectrometer of claim 18, wherein the electric field pushes the at least one ion away from the plate.

20. The time-of-flight ion mass spectrometer of claim 19, wherein the timer uses the pulse applied to the electrode closest to the entrance opening of the chamber.

The invention claimed is:

1. A gating apparatus in an ion mass spectrometer comprising:

2. The gating apparatus of claim 1, wherein the electrical signal is a plurality of pulses with temporal pulse width and the plurality of pulses are applied at a pulse frequency.

3. The gating apparatus of claim 2, wherein the pulse frequency is a function of the position of the plurality of electrodes and ion velocity.

4. The gating apparatus of claim 3, wherein the temporal pulse width is between 1 ns to 100 ns and the pulse frequency is between 2 ns to 100 ns.

5. The gating apparatus of claim 4, wherein the electric gate is a field programmable gate array.

6. The gating apparatus of claim 5, wherein the electrical signal pushes the at least one ion away from the plate having the plurality of electrodes.

7. The gating apparatus of claim 5, wherein a start time for time-of-flight analyses is the pulse applied to the electrode closest to the entrance opening of the chamber.

8. A method for gating an ion mass spectrometer comprising:

9. The method of claim 8, wherein the electrical signal is a plurality of pulses with temporal pulse width and the plurality of pulses are applied at a pulse frequency.

10. The method of claim 9, wherein the pulse frequency is a function of the position of the plurality of electrodes and ion velocity.

11. The method of claim 10, wherein the temporal pulse width is between 1 ns to 100 ns and the pulse frequency is between 2 ns to 100 ns.

12. The method of claim 11, wherein the electric signal is applied by a field programmable gate array.

13. The method of claim 12, wherein the electrical signal pushes the at least one ion away from the plate having the plurality of electrodes.

14. The method of claim 13, wherein a start time for time-of-flight analyses is the pulse applied to the electrode closest to the entrance opening of the chamber.

15. A time-of-flight ion mass spectrometer comprising:

16. The time-of-flight ion mass spectrometer of claim 15, wherein the field programmable array generates a plurality of pulses with temporal pulse width and the plurality of pulses are applied at a pulse frequency.

17. The time-of-flight ion mass spectrometer of claim 16, wherein the pulse frequency is a function of the position of the plurality of electrodes and ion velocity.

18. The time-of-flight ion mass spectrometer of claim 16, wherein the temporal pulse width is between 1 ns to 100 ns and the pulse frequency is between 2 ns to 100 ns.

19. The time-of-flight ion mass spectrometer of claim 18, wherein the electric field pushes the at least one ion away from the plate.

20. The time-of-flight ion mass spectrometer of claim 19, wherein the timer uses the pulse applied to the electrode closest to the entrance opening of the chamber.

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